



# UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE  
United States Patent and Trademark Office  
Address: COMMISSIONER FOR PATENTS  
P.O. Box 1450  
Alexandria, Virginia 22313-1450  
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/605,449	09/30/2003	Dennis R. Conti	BUR920030050US1	2448

26679 7590 03/29/2007  
DRIGGS, HOGG & FRY CO. L.P.A.  
38500 CHARDON ROAD  
DEPT. IBU  
WILLOUGHBY HILLS, OH 44094

EXAMINER
----------

HOLLINGTON, JERMELE M

ART UNIT	PAPER NUMBER
----------	--------------

2829

SHORTENED STATUTORY PERIOD OF RESPONSE	MAIL DATE	DELIVERY MODE
3 MONTHS	03/29/2007	PAPER

**Please find below and/or attached an Office communication concerning this application or proceeding.**

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

<b>Office Action Summary</b>	<b>Application No.</b> 10/605,449	<b>Applicant(s)</b> CONTI ET AL.	
	<b>Examiner</b> Jermele M. Hollington	<b>Art Unit</b> 2829	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

**Period for Reply**

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

**Status**

- 1) ☒ Responsive to communication(s) filed on 01 November 2006.
- 2a) ☐ This action is **FINAL**.                      2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

**Disposition of Claims**

- 4) ☒ Claim(s) 1-12 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) ☒ Claim(s) 1-6 is/are allowed.
- 6) ☒ Claim(s) 7-12 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

**Application Papers**

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on \_\_\_\_\_ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

**Priority under 35 U.S.C. § 119**

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All    b) ☐ Some \* c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

**Attachment(s)**

- |  |   |
|--|---|
| 1) <input type="checkbox"/> Notice of References Cited (PTO-892)   | 4) <input type="checkbox"/> Interview Summary (PTO-413)<br>Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948)                       | 5) <input type="checkbox"/> Notice of Informal Patent Application                       |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO/SB/08)<br>Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____  |

## **DETAILED ACTION**

### ***Response to Arguments***

1. Applicant's arguments, see "Arguments", filed November 1, 2006, with respect to claims 1-6 have been fully considered and are persuasive. The 35 U.S.C. 102 rejections of claims 1-6 have been withdrawn.

Regarding claims 7-10, the examiner believes the rejection is valid base on MPEP 2114. MPEP 2114 states that while features of an apparatus may be recited either structurally or functionally, claims directed to an apparatus must be distinguished from the prior art in terms of structure rather than function alone. In other words, a recitation directed to the manner in which a claimed apparatus is intended to be used does not distinguished the claimed apparatus from the prior art.

### ***Claim Rejections - 35 USC § 102***

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

3. Claims 7-10 are rejected under 35 U.S.C. 102(b) as being anticipated by Iino et al (5568054).

Regarding claims 7-8, Iino et al disclose [see Fig. 6] controlling the burning in of at least one I/C chip (IC chip on wafer W) in a burn in tool (inspection section 12), wherein said tool (12) has a device (probe card 20) for mounting each chip (IC on wafer W) to be burned in, and a

Art Unit: 2829

power source (power source 40) to supply electrical current to burn in each chip (IC on wafer W), comprising the steps of: continuously monitoring [via measuring section 41] at least one electrical value input to each chip (on wafer W) wherein the current value is maintain at or below a given value [see col. 2, lines 9-30, col. 5, lines 3-63, col. 6, lines 29-37 and col. 7, line 47-col. 8, line 13].

Regarding claim 9, Iino et al disclose [see Fig. 6] at least one electrical value input to each chip (on wafer W) wherein the power value is maintain at or below a given value [see col. 2, lines 9-30, col. 5, lines 3-63, col. 6, lines 29-37 and col. 7, line 47-col. 8, line 13].

Regarding claim 10, Iino et al disclose a monitor (measuring section 41) to continuously monitor the temperature value of each chip (W) being burned in and wherein the voltage is varied to maintain the temperature value of each device at a given value [see col. 2, lines 9-30, col. 5, lines 3-63, col. 6, lines 29-37 and col. 7, line 47-col. 8, line 13].

4. Claims 7, and 10-12 are rejected under 35 U.S.C. 102(b) as being anticipated by Hamilton (5911897).

Regarding claim 7, Hamilton discloses a burn in tool (burn in board 10) for burning in at least one I/C chip (IC chip 12) comprising: a structure (heat sink assembly 24) for mounting each chip (12) to be burned in; a power source (V REF) to supply electrical current to burn in each chip (12); a structure (sensor housing 44) for continuously monitoring at least one electrical value input to each chip (12) selected from the group of current, voltage and power, and a structure to vary the voltage to maintain at least one of the values at or below a given value.

Art Unit: 2829

Regarding claim 10 Hamilton discloses a monitor (temperature sensor 48) to continuously monitor the temperature value of each chip (12) being burned in and wherein the voltage is varied to maintain the temperature value of each device at a given value.

Regarding claim 11, Hamilton discloses a heat sink (heat sink 34) is in contact with each device (24).

Regarding claim 12, Hamilton discloses the tool (10) has a heat sink (heat sink 34) and temperature monitor (48) for each device (24) and each heat sink (34) has means (48) to control the temperature of the heat sink (34), and the temperature control means (22) is varied to maintain the temperature value of each device (24) at a given value.

### ***Conclusion***

5. Claims 1-6 are allowed.

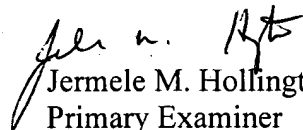
6. The following is a statement of reasons for the indication of allowable subject matter: regarding claim 1, the reason for the allowance is due to a method of controlling the burning in of at least one IC chip in a burn in tool having a monitor for each chip to continuously monitor the temperature value of each chip. Since claims 2-6 depend from claim 1, they also have allowable subject matter.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jermele M. Hollington whose telephone number is (571) 272-1960. The examiner can normally be reached on M-F (9:00-4:00 EST) First Friday Off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Ha Nguyen can be reached on (571) 272-1678. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Art Unit: 2829

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

  
Jermele M. Hollington  
Primary Examiner  
Art Unit 2829

JMH  
March 27, 2007